Docket No.: 42P14242X

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re the Application of:

HORST HAUSSECKER, ET AL.

Application No.:

Filed:

For: Model-Based Fusion of Scanning Probe

Microscopic Images for Detection and Identification of Molecular Structures

Art Group: 1645

Examiner: Not yet assigned

## INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §1.97

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure, enclosed is a copy of Information Disclosure Statement by Applicant (form PTO/SB/08), which is being submitted concurrently with the Continuation-in-Part Application. It is respectfully requested that the cited references be considered and that the enclosed copy of PTO/SB/08 be initialed by the Examiner to indicate such consideration and a copy thereof returned to applicant(s). Some or all of the references listed on the enclosed PTO/SB/08 were previously identified in the parent application (Application No. 10/273,312, filed October 17, 2002) and copies of the references were furnished at that time. Accordingly, per 37 CFR §1.98(d)(1) additional copies of those references are not submitted herewith.

-1- 42P14242X

The submission of this Information Disclosure Statement is not to be construed as a representation that a search has been made in the subject application and is not to be construed as an admission that the information cited in this statement is material to patentability.

Please charge any fees due to Deposit Account 02-2666. A duplicate copy of the Fee Transmittal (PTO/SB/17) is enclosed for this purpose.

Respectfully submitted,

BLAKELY, SOKOLOFF, TAYLOR & ZAFMAN LLP

Date: 10/14/03

Richard A. Nakashima, Reg. No. 42,023

12400 Wilshire Blvd., 7th Floor Los Angeles, California 90025 (303) 740-1980 Please type a plus sign (+) in this box

Sheet

U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE
Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number

Substitute for form 1449A/PTO

(modified)

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

First Na

of

3

(use as many sheets as necessary)

Complete if known				
Application Number Not yet assigned				
Filing Date Concurrently Herewith				
First Named Inventor	Horst Haussecker			
Group Art Unit	Not yet assigned			
Examiner Name	Not yet assigned			
Attorney Docket	42P14242X			

U.S. PATENT DOCUMENTS						
Examiner Initials	Cite No.1	U.S. Patent Document Number	Kind Code <sup>2</sup> (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines Where Relevant Passage or Figures Appear
		5,472,881		Beebe, et al.	12/05/1995	
		5,497,656		Kado, et al.	03/12/1996	
		6,044,221		Gupta, et al.	03/28/2000	
		6,078,681		Silver	06/20/2000	
		6,157,921		Barnhill	12/05/2000	
<del></del> :		6,195,445		Dubuisson-Jolly, et al.	02/27/2001	
		6,259,802		Jolly, et al.	07/10/2001	
		6,280,939		Allen	08/28/2001	
		6,327,581		Platt	12/04/2001	
		6,345,235		Edgecombe, et al.	02/05/2002	
		6,360,020		Panis	03/19/2002	

		OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS	
Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date page(s), volume-issue number(s), publisher, city and/or country where published.	$T^2$
		United States Patent Application Publication, Publication No. US	
		2001/0052257, Magerle, Publication Date December 20, 2001.	

Examiner Signature	Date Considered	
	 	<del></del>

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Unique citation designation number.

2 See attached Kinds of U.S. Patent Documents.

3 Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3).

4 For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document.

5 Kind of document by the appropriate symbols as indicated on the document under WIPO Standard St.16 if possible.

6 Applicant is to place a check mark here if English language Translation is attached.

U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number

Substitute for form 1449A/PTO Complete if known (modified) **Application Number** Not yet assigned INFORMATION DISCLOSURE **Filing Date** Concurrently Herewith STATEMENT BY APPLICANT **First Named Inventor** Horst Haussecker **Group Art Unit** Not yet assigned (use as many sheets as necessary) **Examiner Name** Not yet assigned Sheet 2 3 of 42P14242X Attorney Docket

Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date page(s), volume-issue number(s),	
		publisher, city and/or country where published.	•
1		ANDO, et al., "A High-Speed Atomic Force Microscope for Studying	
		Biological Macromolecules," PNAS, Vol. 98, No. 22, pp. 12468-12472,	
		October 2001.	
		CLAUSS, et al., "Atomic Resolution STM Imaging of a Twisted Single-Wall	
		Carbon Nanotube," <i>Physical Review B</i> , Volume 58, Number 8, pp. 4266-4269, August 1998.	
		CLAUSS, et al., "Electron Backscattering on Single-Wall Carbon Nanotubes Observed by Scanning Tunneling Microscopy," <i>Europhys. Lett,</i> 47(5), pp. 601-607, 1999.	
		FREITAG, et al., "Local Electronic Properties of Single-Wall Nanotube Circuits Measured by Conducting-Tip AFM," <i>Physical Review B</i> , Volume 62, Number 4, pp. 2307-2310, July 2000.	
		FRISBIE, et al, "Functional Group Imaging by Chemical Force Microscopy," Science, Vol. 265, pp. 2071-2074, September 1994.	
		HANSMA, et al., Atomic Force Microscopy of DNA in Aqueous Solutions," <i>Nucleic Acids Res.</i> , 21:505-512, 1993.	
		HIRAHARA, et al., "One-Dimensional Metallofullerene Crystal Generated Inside Single-Walled Carbon Nanotubes," <i>Physical Review Letters</i> , Volume 85, Number 25, pp. 5384-5387, December 2000.	
		HUANG, et al., "Directed Assembly of One-Dimensional Nanostructures into Functional Networks," <i>Science</i> , Vol. 291, pp. 630-633, January 2001.	
		KIM, et al., "AFM Study of Surface Phenomena Based on C <sub>60</sub> Film Growth," <i>Applied Surface Science</i> , 130-132, pp.602-609, 1998.	
		KLEIN, et al., "Ordered Stretching of Single Molecules of Deoxyribose Nucleic Acid Between Microfabricated Polystyrene Lines," <i>Applied Physics Letters</i> , Vol. 78, Number 16, pp. 2396-2398, April 2001.	

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in

conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup> Unique citation designation number. <sup>2</sup> See attached Kinds of U.S. Patent Documents. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard St.16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

Please type a plus sign (+) in this box	+
	1

U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number

Substitute for form 1449A/PTO			РТО	Complete if known		
	(modi	•		Application Number	Not yet assigned	
	RMATION			Filing Date	Concurrently Herewith	
STATEMENT BY APPLICANT			ICANI	First Named Inventor	Horst Haussecker	
(use as many sheets as necessary)				Group Art Unit	Not yet assigned	
•				Examiner Name	Not yet assigned	
Sheet	3 of 3	3	Attorney Docket	42P14242X		

	<u> </u>	OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS	-
Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date page(s), volume-issue number(s), publisher, city and/or country where published.	Т
		KOBAYASHI, et al., "Imaging of Fullerene Molecules on Si(111)-7 7 Surface with NC-AFM," <i>Applied Surface Science</i> , 157, pp. 228-232, 2000.	
		MÖLLER, et al, "Tapping-Mode Atomic Force Microscopy Produces Faithful High-Resolution Images of Protein Surfaces," <i>Biophys. J.</i> , 77:1150-8, 1999.	
		MURRAY, et al., "Atomic Force Microscopy of Biochemically Tagged DNA," Proc. Natl. Acad. Sci. USA, 90:3811-4, 1993.	
		NICEWARMER-PEÑA, "Submicrometer Metallic Barcodes," <i>Science</i> , Vol. 294, pp. 137-141, October 2001.	
		ODOM, et al., "Single-Walled Carbon Nanotubes," <i>Ann. N.Y. Acad. Sci.</i> , 960: 203-215, (2002). Retrieved from the Internet on July 2, 2002, URL:// <a href="http://annalsnyas.org/cgi/content/full/960/1/203">http://annalsnyas.org/cgi/content/full/960/1/203</a> 10 pages.	
		THUNDAT, et al., "Atomic Force Microscopy of DNA on Mice and Chemically Modified Mica," Scanning Microsc. 6:911-8, 1992.	
		UCHIHASHI, et al, "Application of Noncontact-Mode Atomic Force Microscopy to Molecular Imaging," Retrieved from the Internet on July 3, 2002, URL:// <a href="http://www.foresight.org/Conferences/MNT7/Abstracts/Uchihashi/">http://www.foresight.org/Conferences/MNT7/Abstracts/Uchihashi/</a> 2	
		pages.	

Examiner Signature	Date Considered	
-----------------------	--------------------	--

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in

conformance and not considered. Include copy of this form with next communication to applicant.

1 Unique citation designation number. See attached Kinds of U.S. Patent Documents. Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. Kind of document by the appropriate symbols as indicated on the document under WIPO Standard St.16 if possible. Applicant is to place a check mark here if English language Translation is attached.